TOSHIBA HIGH EFFICIENCY DIODE STACK (HED) SILICON EPITAXIAL TYPE

20DL2C48A, U20DL2C48A, 20FL2C48A, U20FL2C48A

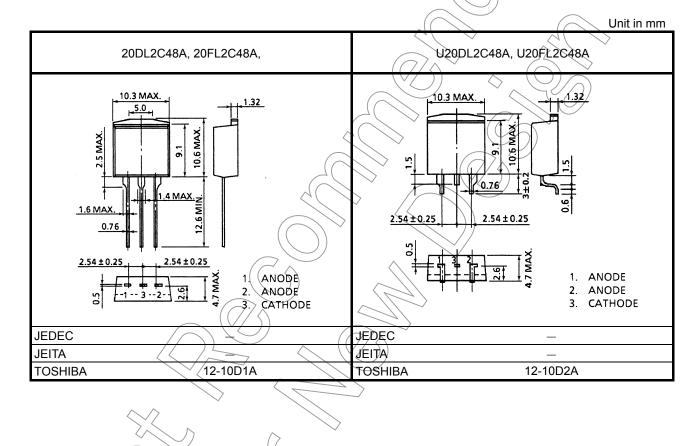
SWITCHING MODE POWER SUPPLY APPLICATION CONVERTER & CHOPPER APPLICATION

• Repetitive Peak Reverse Voltage : VRRM = 200 V, 300 V

• Average Output Rectified Current $: I_O = 20 \text{ A}$

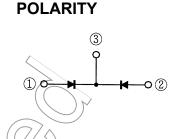
• Ultra Fast Reverse-Recovery Time $: t_{rr} = 35 \text{ ns (Max)}$

• Low Switching Losses and Output Noise



ABSOLUTE MAXIMUM RATINGS (Ta = 25°C)

CHARACTERISTIC		SYMBOL	RATING	UNIT	
	20DL2C48A		200		
Repetitive Peak Reverse Voltage	U20DL2C48A	VRRM	200	V	
	20FL2C48A	VKKIVI	300	V	
	U20FL2C48A		300		
Average Output Rectified Current		Ю	20	Α	
Peak One Cycle Surge Forward Current		IFSM	100 (50Hz)	А	
		יראויו	110 (60Hz)	A <	
Junction Temparature		Tj	-40~150	°C	
Storage Temparature Range		T _{stg}	-40~150	°C	



Note: Using continuously under heavy loads (e.g. the application of high temperature/current/voltage and the significant change in temperature, etc.) may cause this product to decrease in the reliability significantly even if the operating conditions (i.e. operating temperature/current/voltage, etc.) are within the absolute maximum ratings.

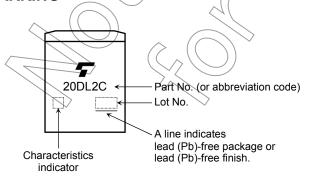
Please design the appropriate reliability upon reviewing the Toshiba Semiconductor Reliability Handbook ("Handling Precautions"/Derating Concept and Methods) and individual reliability data (i.e. reliability test report and estimated failure rate, etc).

ELECTRICAL CHARACTERISTICS (Ta = 25°C)

CHARACTERISTIC		SYMBOL	TEST CONDITION	MIN.	TYP.	MAX.	UNIT
Peak Forward Voltage	20DL2C48A		I _{FM} =10A	_	_	0.98	
	U20DL2C48A	VFM					· V
	20FL2C48A			_	_	1.3	
	U20FL2C48A						
Repetitive Peak Revers	e Current	√IRRM	V _{RRM} ≅Rated			50	μΑ
Reverse Recovery Time) t _{rr}	IF≠2A, di / dt=−50A / μs			35	ns
Forward Recovery Time		tfr	IP=VA			100	ns
Thermal Resistance		R _{th} (j-c)	Total DC	_		1.6	°C/W

V_{FM}, I_{RRM}, t_{rr}, t_{fr}: A Value applied to one cell.

MARKING



Abbreviation Code	Part No.		
20DL2C	20DL2C48A		
20DL2C	U20DL2C48A		
20FL2C	20FL2C48A		
20FL2C	U20FL2C48A		

Handling Precaution

The absolute maximum ratings denote the absolute maximum ratings, which are rated values and must not be exceeded during operation, even for an instant. The following are the general derating methods that we recommend when you design a circuit with a device.

VRRM: We recommend that the worst case voltage, including surge voltage be no greater than 80% of the absolute maximum rating of VRRM for a DC circuit and be no greater than 50% of that of VRRM for an AC circuit. VRRM has a temperature coefficient of 0.1%/°C. Take this temperature coefficient into account designing a device at low temperature.

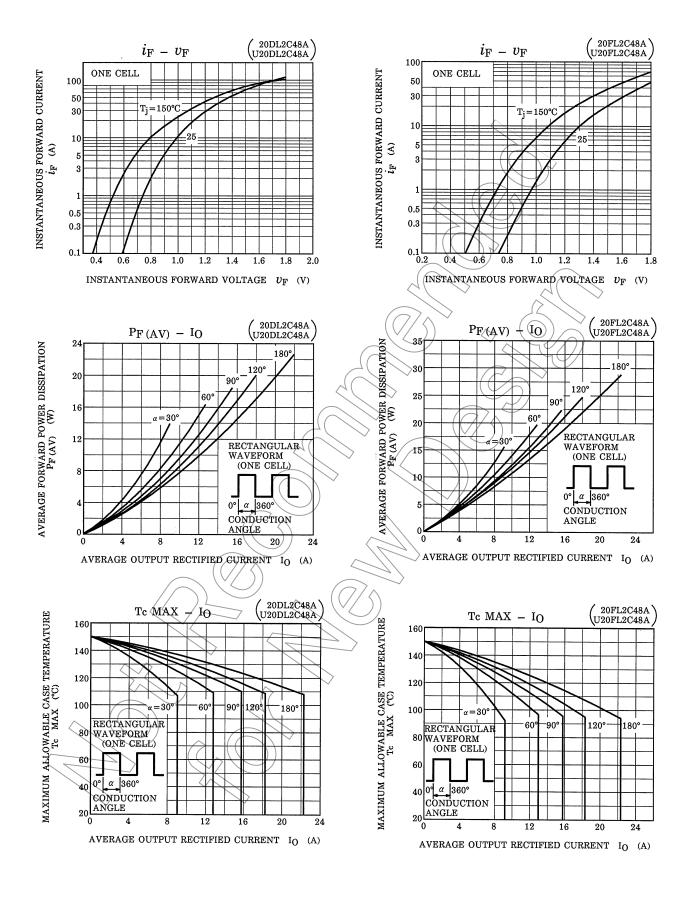
Io: We recommend that the worst case current be no greater than 80% of the absolute maximum rating of Io. Carry out adequate heat design. If you can't design a circuit with excellent heat radiation, set the margin by using an allowable Tamax-Io curve.

This rating specifies the non-repetitive peak current in one cycle of a 50 Hz sine wave, condition angle 180. Therefore, this is only applied for an abnormal operation, which seldom occurs during the lifespan of the device.

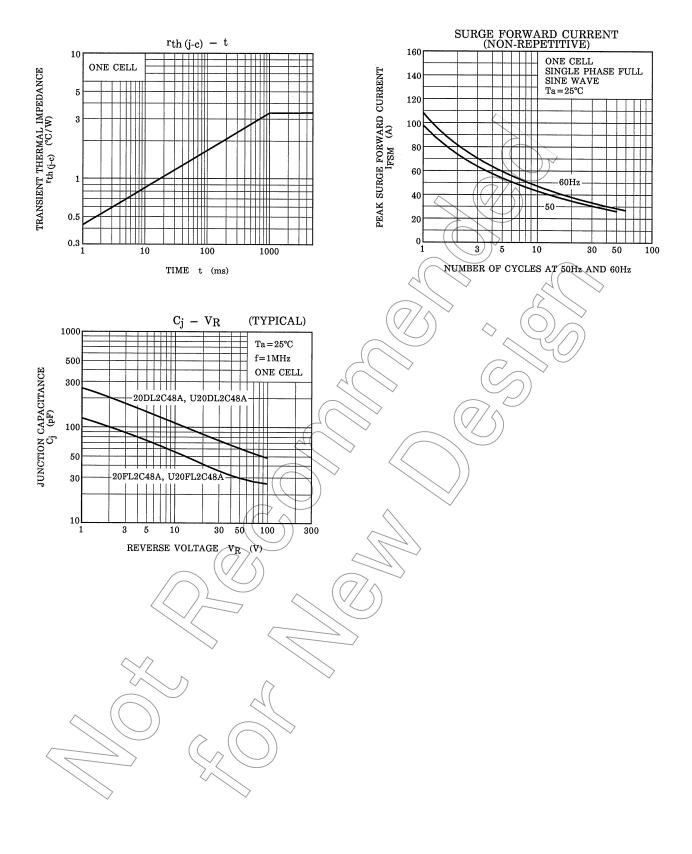
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We recommend that a device be used at a Tj of below 120°C under the worst load and heat radiation conditions.





4





RESTRICTIONS ON PRODUCT USE

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- · The information contained herein is subject to change without notice.
- TOSHIBA is continually working to improve the quality and reliability of its products. Nevertheless, semiconductor devices in general can malfunction or fail due to their inherent electrical sensitivity and vulnerability to physical stress. It is the responsibility of the buyer, when utilizing TOSHIBA products, to comply with the standards of safety in making a safe design for the entire system, and to avoid situations in which a malfunction or failure of such TOSHIBA products could cause loss of human life, bodily injury or damage to property. In developing your designs, please ensure that TOSHIBA products are used within specified operating ranges as set forth in the most recent TOSHIBA products specifications. Also, please keep in mind the precautions and conditions set forth in the "Handling Guide for Semiconductor Devices," or "TOSHIBA Semiconductor Reliability Handbook" etc.
- The TOSHIBA products listed in this document are intended for usage in general electronics applications (computer, personal equipment, office equipment, measuring equipment, industrial robotics, domestic appliances, etc.). These TOSHIBA products are neither intended nor warranted for usage in equipment that requires extraordinarily high quality and/or reliability or a malfunction or failure of which may cause loss of human life or bodily injury ("Unintended Usage"). Unintended Usage include atomic energy control instruments, airplane or spaceship instruments, transportation instruments, traffic signal instruments, combustion control instruments, medical instruments, all types of safety devices, etc.. Unintended Usage of TOSHIBA products listed in his document shall be made at the customer's own risk.
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6 2006-11-08